

## TEST REPORT EN 60269-4

## Low-voltage fuses

## Part 4: Supplementary requirements for fuse-links for the protection of semiconductor devices

**Report Number.....:** 03601-A-23D0186-S

Date of issue.....: 2024-04-15

Total number of pages ..... 28

Name of Testing Laboratory Suzhou Electrical Apparatus Science Research Institute Co.,

preparing the Report .....: Ltd.(EETI)

Applicant's name ...... Zhejiang Tengen Electric Co., Ltd.

Province, P.R.China.

Test specification:

EN 60269-4:2009/AMD2:2016

Test procedure .....: CCA Scheme

Non-standard test method .....: N/A

**TRF template used.....:** IECEE OD-2020-F1:2022, Ed.1.5

Test Report Form No. ..... EN60269 4D

Test Report Form(s) Originator ....: CQC

Master TRF.....: Dated 2023-08-17

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Test item description:		Fuse for protection of semiconductor devices			
Trademark(s):		Tengen			
Manufacturer:		Zhejiang Tengen Electric Co., Ltd.			
		Sulv Industry Zone, Liushi Town, Yueqing City, Zhejiang Province, P.R.China.			
Model/Type reference		TGRS	TGRS3Z-NEP		
Ratings: See		See Pa	e Page 6		
				以此所及	
Res	ponsible Testing Laboratory (as a	pplical	ole), testing procedure	and testing location(s):	
☐ CB Testing Laboratory:		Suzhou Electrical Appar Co., Ltd.(EETI)	ratus Science Research Institute		
Testing location/ address:		No.7 Yonghe Street, Bir China	hhe Road New District, Suzhou,		
Tested by (name, function, signature):			Fang Gang (Team leader)	为例	
Арр	roved by (name, function, signatu	ıre):	Sun Aqin (Supervisor)	3003	
	Testing procedure: CTF Stage 1:			,	
Testing location/ address:					
1031	ing location, address				
Tested by (name, function, signature):					
Approved by (name, function, signature):					
☐ Testing procedure: CTF Stage 2:					
Testing location/ address:					
Tested by (name + signature):					
Witnessed by (name, function, signature). :					
Approved by (name, function, signature):					
	Testing procedure: CTF Stage 3:				
	Testing procedure: CTF Stage 4:				
Testing location/ address:					
Tested by (name, function, signature):					
Witnessed by (name, function, signature). :					
Approved by (name, function, signature):					
Supervised by (name, function, signature) :					